Freescale Semiconductor - MSC8144VT800B Datasheet

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Understanding Embedded - DSP (Digital Signal Processors)

Embedded - DSP (Digital Signal Processors) are specialized microprocessors designed to perform complex mathematical computations on digital signals in real-time. Unlike general-purpose processors, DSPs are optimized for high-speed numeric processing tasks, making them ideal for applications that require efficient and precise manipulation of digital data. These processors are fundamental in converting and processing signals in various forms, including audio, video, and communication signals, ensuring that data is accurately interpreted and utilized in embedded systems.

Applications of Embedded - DSP (Digital Signal Processors)

Details	
Product Status	Active
Type	SC3400 Core
Interface	Ethernet, I²C, SPI, TDM, UART, UTOPIA
Clock Rate	800MHz
Non-Volatile Memory	External
On-Chip RAM	10.5MB
Voltage - I/O	3.30V
Voltage - Core	1.00V
Operating Temperature	0°C ~ 90°C (TJ)
Mounting Type	Surface Mount
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=msc8144vt800b

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

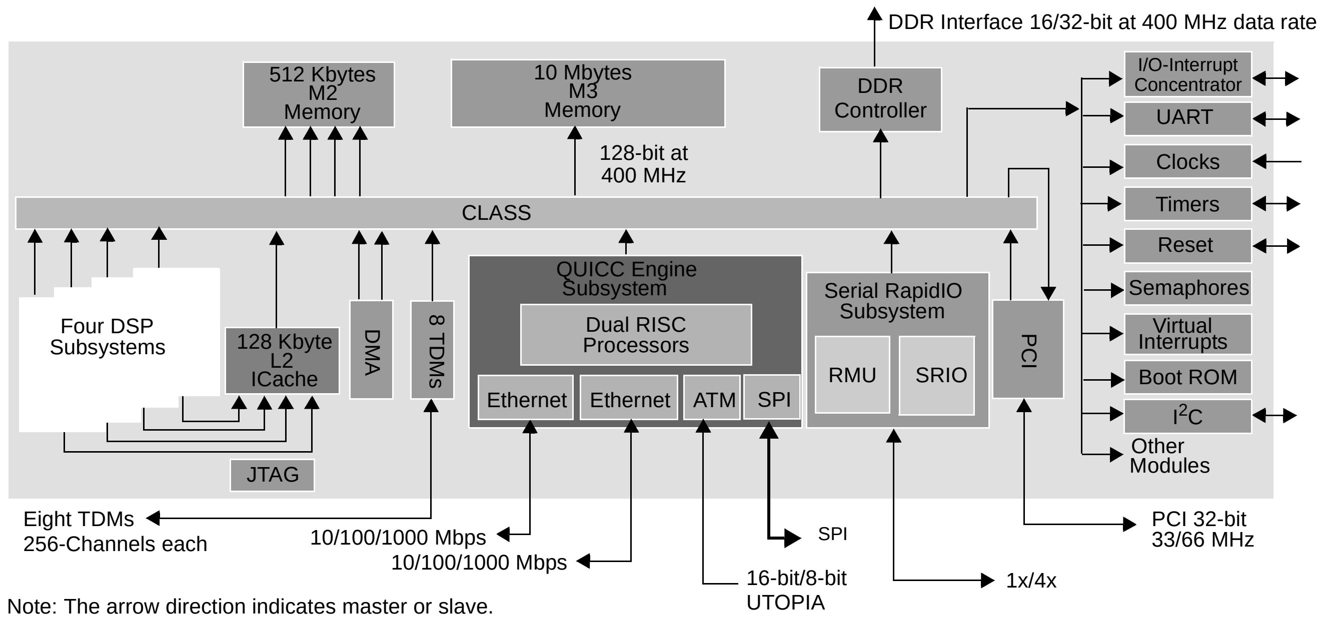

Figure 1. MSC8144 Block Diagram

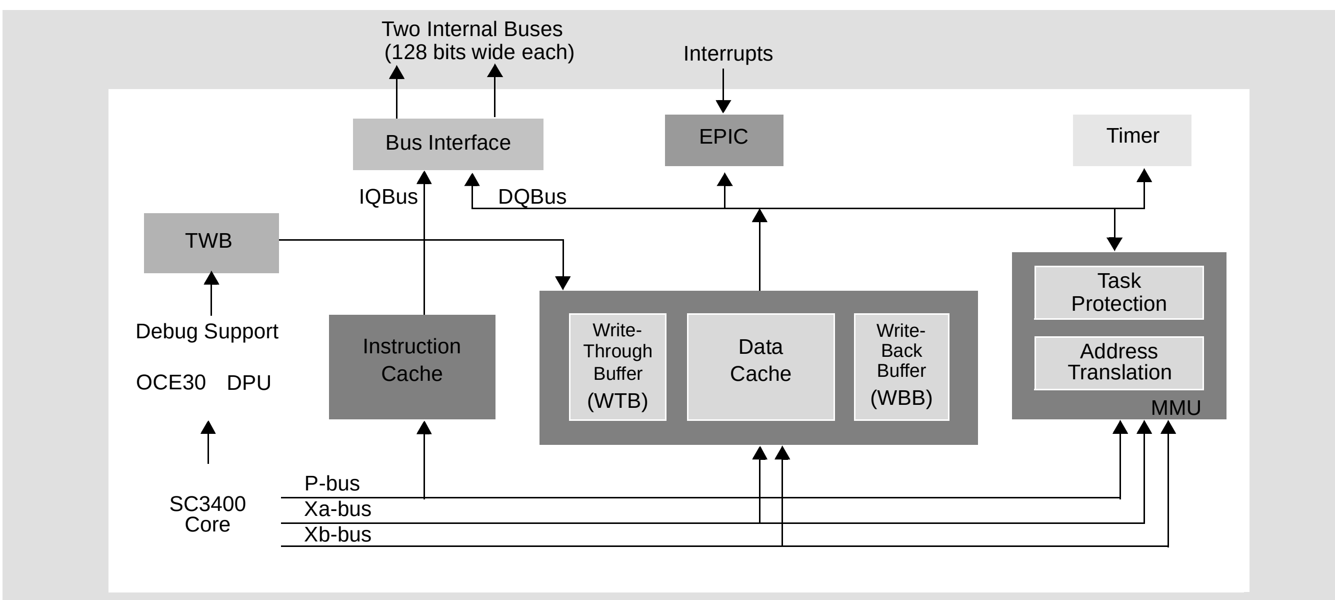

Figure 2. StarCore SC3400 DSP Core Subsystem Block Diagram

1 Pin Assignments and Reset States

This section includes diagrams of the MSC8144 package ball grid array layouts and tables showing how the pinouts are allocated for the package.

1.1 FC-PBGA Ball Layout Diagrams

Top and bottom views of the FC-PBGA package are shown in Figure 3 and Figure 4 with their ball location index numbers.

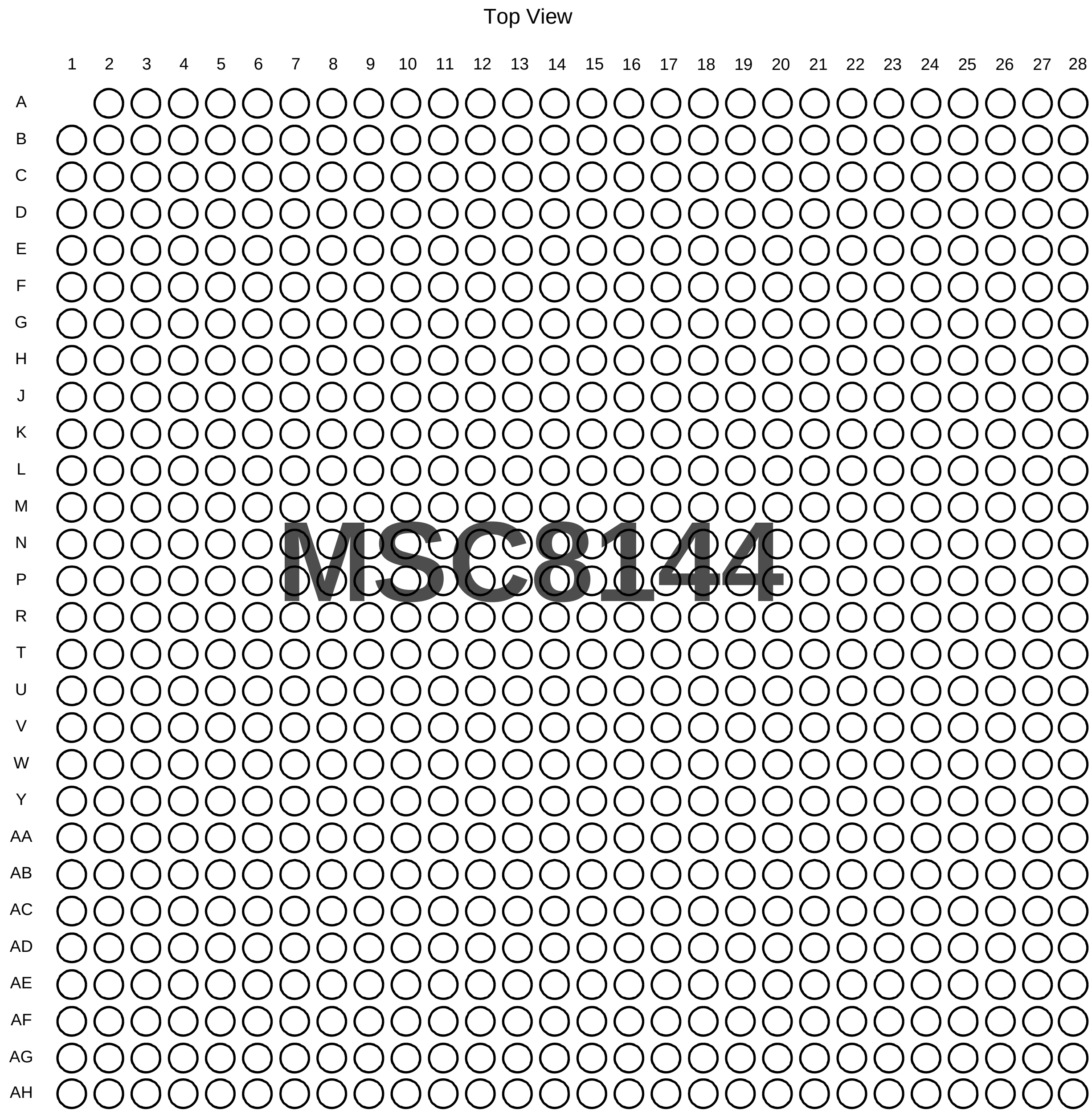

Figure 3. MSC8144 FC-PBGA Package, Top View

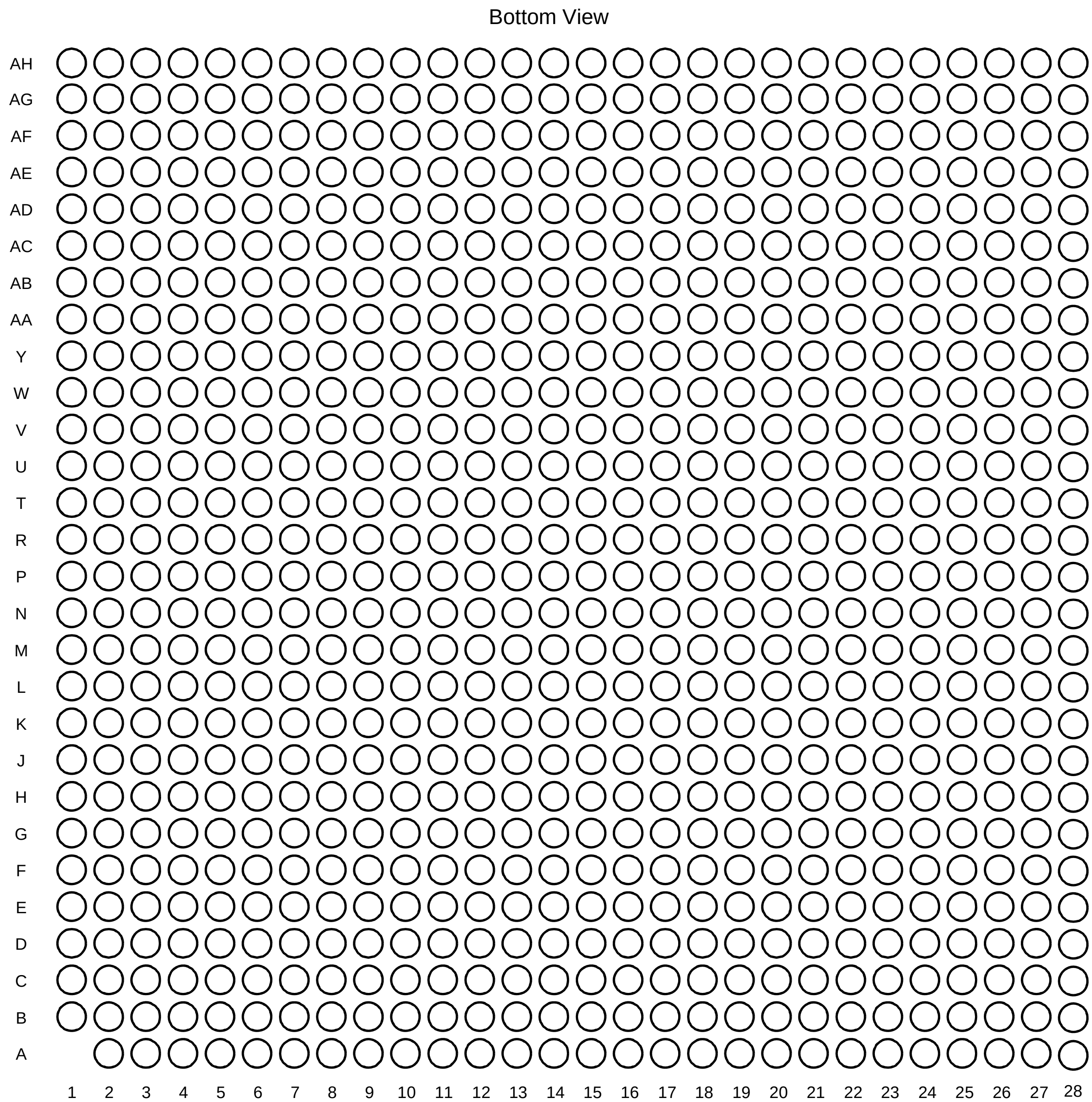

Figure 4. MSC8144 FC-PBGA Package, Bottom View

Ball Number	Signal Name	Power-On Reset Value	I/O Multiplexing Mode[2] 0 (000)	1 (001)	2 (010)	3 (011)	4 (100)	5 (101)	6 (110)	7 (111)	Ref. Supply
B10	Reserved[1]										—
B11	Reserved[1]										—
B12	SRIO_RXD0										V_{DDSXC}
B13	GND_{SXC}										GND_{SXC}
B14	SRIO_RXD1										V_{DDSXC}
B15	GND_{SXC}										GND_{SXC}
B16	SRIO_REF_CLK										V_{DDSXC}
B17	Reserved[1]										—
B18	V_{DDSXC}										V_{DDSXC}
B19	SRIO_RXD2/ GE1_SGMII_RX		SGMII support on SERDES is enabled by Reset Configuration Word								V_{DDSXC}
B20	GND_{SXC}										GND_{SXC}
B21	SRIO_RXD3/ GE2_SGMII_RX		SGMII support on SERDES is enabled by Reset Configuration Word								V_{DDSXC}
B22	GND_{SXC}										GND_{SXC}
B23	GND_{SXP}										GND_{SXP}
B24	MDQ27										V_{DDDDR}
B25	V_{DDDDR}										V_{DDDDR}
B26	GND										GND
B27	V_{DDDDR}										V_{DDDDR}
B28	MDQS3										V_{DDDDR}
C1	Reserved[1]										—
C2	GE2_RX_CLK/PCI_AD29		Ethernet 2				PCI	Ethernet 2			V_{DDGE2}
C3	V_{DDGE2}										V_{DDGE2}
C4	TDM7RSYN/GE2_TD2/ PCI_AD2/UTP_TER		TDM		PCI			Ethernet 2		UTOPIA	V_{DDGE2}
C5	TDM7RCLK/GE2_RD2/ PCI_AD0/UTP_RVL		TDM		PCI			Ethernet 2		UTOPIA	V_{DDGE2}
C6	V_{DDGE2}										V_{DDGE2}
C7	GE2_RD0/PCI_AD27		Ethernet 2				PCI	Ethernet 2			V_{DDGE2}
C8	Reserved[1]										—
C9	Reserved[1]										—
C10	Reserved[1]										—
C11	Reserved[1]										—
C12	V_{DDSXP}										V_{DDSXP}
C13	SRIO_TXD0										V_{DDSXP}
C14	V_{DDSXP}										V_{DDSXP}
C15	SRIO_TXD1										V_{DDSXP}
C16	GND_{SXC}										GND_{SXC}
C17	GND_{RIOPLL}										GND_{RIOPLL}
C18	Reserved[1]										—
C19	V_{DDSXP}										V_{DDSXP}
C20	SRIO_TXD2/GE1_SGMII_TX		SGMII support on SERDES is enabled by Reset Configuration Word								V_{DDSXP}

Table 1. Signal List by Ball Number (continued)

Ball Number	Signal Name	Power-On Reset Value	I/O Multiplexing Mode[2]								Ref. Supply
			0 (000)	1 (001)	2 (010)	3 (011)	4 (100)	5 (101)	6 (110)	7 (111)	
N22	GND										GND
N23	MODT1										V_{DDDDR}
N24	MCKE0										V_{DDDDR}
N25	V_{DDDDR}										V_{DDDDR}
N26	MA5										V_{DDDDR}
N27	MA6										V_{DDDDR}
N28	MA11										V_{DDDDR}
P1	Reserved[1]										—
P2	TDI[5]										V_{DDIO}
P3	UTP_RD11/PCI_AD15		UTOPIA		PCI	UTOPIA					V_{DDIO}
P4	GND										GND
P5	UTP_RADDR3/PCI_AD10		UTOPIA		PCI	UTOPIA					V_{DDIO}
P6	UTP_RADDR2/PCI_AD9		UTOPIA		PCI	UTOPIA					V_{DDIO}
P7	$\overline{PCI\_GNT}$/GPIO29/$\overline{IRQ7}$[3, 6]		GPIO/IRQ		PCI			GPIO/IRQ			V_{DDIO}
P8	$\overline{PCI\_STOP}$/GPIO30/$\overline{IRQ2}$[3, 6]		GPIO/IRQ		PCI			GPIO/IRQ			V_{DDIO}
P9	GND										GND
P10	GND										GND
P11	V_{DDM3}										V_{DDM3}
P12	GND										GND
P13	V_{DDM3}										V_{DDM3}
P14	GND										GND
P15	V_{DDM3}										V_{DDM3}
P16	GND										GND
P17	V_{DDM3}										V_{DDM3}
P18	GND										GND
P19	V_{DDM3}										V_{DDM3}
P20	GND										GND
P21	GND										GND
P22	V_{DDDDR}										V_{DDDDR}
P23	$\overline{MCS0}$										V_{DDDDR}
P24	$\overline{MRAS}$										V_{DDDDR}
P25	GND										GND
P26	V_{DDDDR}										V_{DDDDR}
P27	GND										GND
P28	$\overline{MCK2}$										V_{DDDDR}
R1	Reserved[1]										—
R2	TCK										V_{DDIO}
R3	TDO										V_{DDIO}
R4	UTP_RD12/PCI_AD16		UTOPIA		PCI	UTOPIA					V_{DDIO}
R5	UTP_RCLAV_PDRPA/ PCI_AD12		UTOPIA		PCI	UTOPIA					V_{DDIO}
R6	UTP_RADDR4/PCI_AD11		UTOPIA		PCI	UTOPIA					V_{DDIO}

Table 1. Signal List by Ball Number (continued)

Ball Number	Signal Name	Power-On Reset Value	I/O Multiplexing Mode[2]								Ref. Supply
			0 (000)	1 (001)	2 (010)	3 (011)	4 (100)	5 (101)	6 (110)	7 (111)	
AA7	TDM4TCLK/PCI_AD10		TDM			PCI		TDM			V_{DDIO}
AA8	TDM4TDAT/PCI_AD11		TDM			PCI		TDM			V_{DDIO}
AA9	V_{DDIO}										V_{DDIO}
AA10	V_{DDM3}										V_{DDM3}
AA11	GND										GND
AA12	V_{DDM3}										V_{DDM3}
AA13	GND										GND
AA14	V_{DDM3}										V_{DDM3}
AA15	GND										GND
AA16	V_{DDM3}										V_{DDM3}
AA17	GND										GND
AA18	V_{DDM3}										V_{DDM3}
AA19	GND										GND
AA20	V_{DDM3}										V_{DDM3}
AA21	GND										GND
AA22	GND										GND
AA23	MDQ15										V_{DDDDR}
AA24	MDQ14										V_{DDDDR}
AA25	MDM1										V_{DDDDR}
AA26	MDQ12										V_{DDDDR}
AA27	$\overline{\text{MDQS1}}$										V_{DDDDR}
AA28	MDQS1										V_{DDDDR}
AB1	Reserved[1]										-
AB2	UTP_TSOC/RC15	RC15	UTOPIA								V_{DDIO}
AB3	V_{DDIO}										V_{DDIO}
AB4	TDM6RDAT/PCI_AD20/ GPIO5/$\overline{\text{IRQ11}}$[3, 6]		TDM/GPIO/ IRQ			PCI		TDM/GPIO/ IRQ			V_{DDIO}
AB5	TDM5RDAT/PCI_AD14/ GPIO9[3, 6]		TDM/GPIO			PCI		TDM/GPIO			V_{DDIO}
AB6	TDM6TSYN/PCI_AD24/ GPIO8/ $\overline{\text{IRQ14}}$[3, 6]		TDM/GPIO/IRQ			PCI		TDM/GPIO/IRQ			V_{DDIO}
AB7	TDM6RCLK/PCI_AD19/ GPIO4/$\overline{\text{IRQ10}}$[3, 6]		TDM/GPIO/IRQ			PCI		TDM/GPIO/IRQ			V_{DDIO}
AB8	TDM4RSYN/PCI_AD9		TDM			PCI		TDM			V_{DDIO}
AB9	TDM4RDAT/PCI_AD8		TDM			PCI		TDM			V_{DDIO}
AB10	GND										GND
AB11	V_{DDM3}										V_{DDM3}
AB12	GND										GND
AB13	V_{DDM3}										V_{DDM3}
AB14	GND										GND
AB15	V_{DDM3}										V_{DDM3}
AB16	GND										GND
AB17	V_{DDM3}										V_{DDM3}
AB18	GND										GND

2.3 Default Output Driver Characteristics

Table 4 provides information on the characteristics of the output driver strengths.

Table 4. Output Drive Impedance

Driver Type	Output Impedance (Ω)
DDR signal	18
DDR2 signal	18 35 (half strength mode)

2.4 Thermal Characteristics

Table 5 describes thermal characteristics of the MSC8144 for the FC-PBGA packages.

Table 5. Thermal Characteristics for the MSC8144

Characteristic	Symbol	FC-PBGA 29 × 29 mm[5]		Unit
		Natural Convection	200 ft/min (1 m/s) airflow	
Junction-to-ambient[1, 2]	$R_{\theta JA}$	20	15	°C/W
Junction-to-ambient, four-layer board[1, 3]	$R_{\theta JA}$	15	12	°C/W
Junction-to-board (bottom)[4]	$R_{\theta JB}$	7		°C/W
Junction-to-case[5]	$R_{\theta JC}$	0.8		°C/W

Notes:
1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with the single layer board (JESD51-3) horizontal.
3. Per JEDEC JESD51-6 with the board (JESD51-7) horizontal.
4. Thermal resistance between the die and the printed circuit board per JEDEC JESD 51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the active surface of the die and the case top surface determined by the cold plate method (MIL SPEC-883 Method 1012.1) with the calculated case temperature.

2.5 DC Electrical Characteristics

This section describes the DC electrical characteristics for the MSC8144.

2.5.1 DDR SDRAM DC Electrical Characteristics

This section describes the DC electrical specifications for the DDR SDRAM interface of the MSC8144.

Note: DDR SDRAM uses V_{DDDDR}(typ) = 2.5 V and DDR2 SDRAM uses V_{DDDDR}(typ) = 1.8 V.

2.5.1.1 DDR2 (1.8 V) SDRAM DC Electrical Characteristics

Table 6 provides the recommended operating conditions for the DDR2 SDRAM component(s) of the MSC8144 when V_{DDDDR}(typ) = 1.8 V.

Table 6. DDR2 SDRAM DC Electrical Characteristics for V_{DDDDR} (typ) = 1.8 V

Parameter/Condition	Symbol	Min	Max	Unit
I/O supply voltage[1]	V_{DDDDR}	1.7	1.9	V
I/O reference voltage[2]	MV_{REF}	$0.49 \times V_{DDDDR}$	$0.51 \times V_{DDDDR}$	V
I/O termination voltage[3]	V_{TT}	$MV_{REF} - 0.04$	$MV_{REF} + 0.04$	V
Input high voltage	V_{IH}	$MV_{REF} + 0.125$	$V_{DDDDR} + 0.3$	V
Input low voltage	V_{IL}	–0.3	$MV_{REF} - 0.125$	V
Output leakage current[4]	I_{OZ}	–50	50	μA
Output high current (V_{OUT} = 1.420 V)	I_{OH}	–13.4	—	mA
Output low current (V_{OUT} = 0.280 V)	I_{OL}	13.4	—	mA

Notes:
1. V_{DDDDR} is expected to be within 50 mV of the DRAM V_{DD} at all times.
2. MV_{REF} is expected to be equal to $0.5 \times V_{DDDDR}$, and to track V_{DDDDR} DC variations as measured at the receiver. Peak-to-peak noise on MV_{REF} may not exceed ±2% of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MV_{REF}. This rail should track variations in the DC level of V_{DDDDR}.
4. Output leakage is measured with all outputs are disabled, $0 \text{ V} \leq V_{OUT} \leq V_{DDDDR}$.

2.5.2 Serial RapidIO DC Electrical Characteristics

DC receiver logic levels are not defined since the receiver is AC-coupled.

2.5.2.1 DC Requirements for SerDes Reference Clocks

The SerDes reference clocks SRIO_REF_CLK and $\overline{\text{SRIO\_REF\_CLK}}$ are AC-coupled differential inputs. Each differential clock input has an internal 50 Ω termination to GND_{SXC}. The reference clock must be able to drive this termination. The recommended minimum operating voltage is –0.4 V; the recommended maximum operating voltage is 1.32 V; and the maximum absolute voltage is 1.72 V.

The maximum average current allowed in each input is 8 mA. This current limitation sets the maximum common mode input voltage to be less than 0.4 V (0.4 V/50 Ω = 8 mA) while the minimum common mode input level is GND_{SXC}. For example, a clock with a 50/50 duty cycle can be driven by a current source output that ranges from 0 mA to 16 mA (0–0.8 V). The input is AC-coupled internally, so, therefore, the exact common mode input voltage is not critical.

Note: This internal AC-couple network does not function correctly with reference clock frequencies below 90 MHz.

If the device driving the $\overline{\text{SRIO\_REF\_CLK}}$ inputs cannot drive 50 Ω to GND_{SXC}, or if it exceeds the maximum input current limitations, then it must use external AC-coupling. The minimum differential peak-to-peak amplitude of the input clock is 0.4 V (0.2 V peak-to-peak per phase). The maximum differential peak-to-peak amplitude of the input clock is 1.6 V peak-to-peak (see Figure 5. The termination to GND_{SXC} allows compatibility with HCSL type reference clocks specified for PCI-Express applications. Many other low voltage differential type outputs can be used but will probably need to be AC-coupled due to the limited common mode input range. LVPECL outputs can produce too large an amplitude and may need to be source terminated with a divider network to reduce the amplitude. The amplitude of the clock must be at least a 400 mV differential peak-peak for single-ended clock. If driven differentially, each signal wire needs to drive 100 mV around common mode voltage. The differential reference clock (SRIO_REF_CLK/ $\overline{\text{SRIO\_REF\_CLK}}$) input is HCSL-compatible DC coupled or LVDS-compatible with AC-coupling.

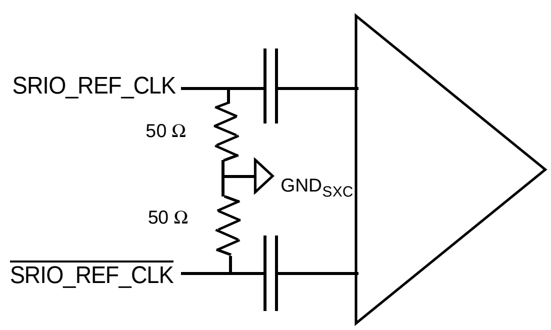

Figure 5. SerDes Reference Clocks Input Stage

2.6 AC Timings

The following sections include illustrations and tables of clock diagrams, signals, and parallel I/O outputs and inputs.

2.6.1 Start-Up Timing

Starting the device requires coordination among several input sequences including clocking, reset, and power. **Section 2.6.2** describes the clocking characteristics. **Section 2.6.3** describes the reset and power-up characteristics. You must use the following guidelines when starting up an MSC8144 device:

- $\overline{PORESET}$ and $\overline{TRST}$ must be asserted externally for the duration of the power-up sequence using the V_{DDIO} (3.3 V) supply. See Table 19 for timing. $\overline{TRST}$ deassertion does not have to be synchronized with $\overline{PORESET}$ deassertion. During functional operation when JTAG is not used, $\overline{TRST}$ can be asserted and remain asserted after the power ramp.

Note: For applications that use M3 memory, $\overline{M3\_RESET}$ should replicate the $\overline{PORESET}$ sequence timing, but using the V_{DDM3IO} (2.5 V) supply. See **Section 3.1.1**, *Power-on Sequence* for additional design information.

- CLKIN should start toggling at least 32 cycles before the $\overline{PORESET}$ deassertion to guarantee correct device operation (see Figure 6). 32 cycles should be accounted only after V_{DDIO} reaches its nominal value.
- CLKIN and PCI_CLK_IN should either be stable low during the power-up of V_{DDIO} supply and start their swings after power-up or should swing within V_{DDIO} range during V_{DDIO} power-up., so their amplitude grows as V_{DDIO} grows during power-up.

Figure 6 shows a sequence in which V_{DDIO} is raised after V_{DD} and CLKIN begins to toggle with the raise of V_{DDIO} supply.

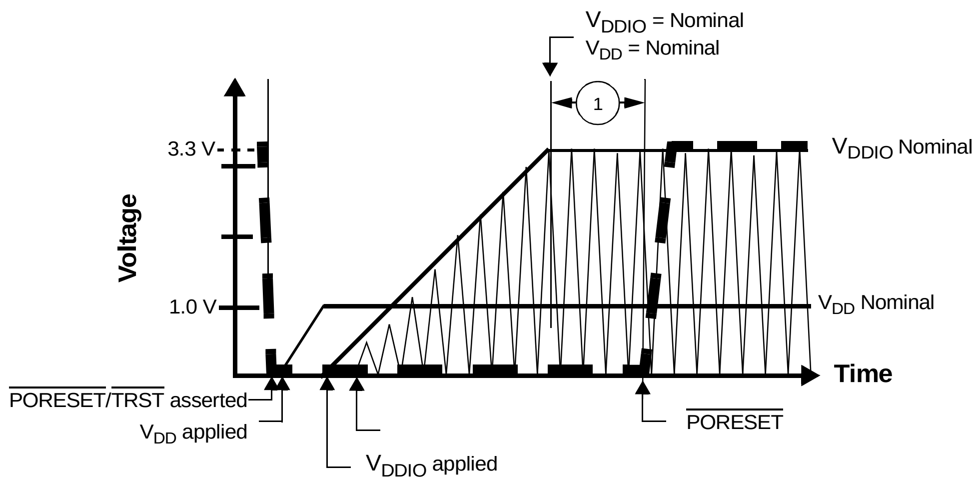

Figure 6. Start-Up Sequence with V_{DD} Raised Before V_{DDIO} with CLKIN Started with V_{DDIO}

2.6.2 Clock and Timing Signals

The following sections include a description of clock signal characteristics. Table 16 shows the maximum frequency values for CLKIN and PCI_CLK_IN. The user must ensure that maximum frequency values are not exceeded.

Table 16. Clock Frequencies

Characteristic	Symbol	Min	Max	Unit
CLKIN frequency	F_{CLKIN}	33	133	MHz
PCI_CLK_IN frequency	$F_{PCI\_CLK\_IN}$	33	133	MHz
CLKIN duty cycle	D_{CLKIN}	40	60	%
PCI_CLK_IN duty cycle	$D_{PCI\_CLK\_IN}$	40	60	%

Table 29. Long Run Transmitter AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output Voltage	V_O	-0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential Output Voltage	V_{DIFFPP}	800	1600	mV_{PP}	
Deterministic Jitter	J_D		0.17	UI_{PP}	
Total Jitter	J_T		0.35	UI_{PP}	
Multiple output skew	S_{MO}		1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	400	400	ps	±100 ppm

Table 30. Long Run Transmitter AC Timing Specifications—3.125 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output Voltage	V_O	-0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential Output Voltage	V_{DIFFPP}	800	1600	mV_{PP}	
Deterministic Jitter	J_D		0.17	UI_{PP}	
Total Jitter	J_T		0.35	UI_{PP}	
Multiple output skew	S_{MO}		1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	320	320	ps	±100 ppm

For each baud rate at which an LP-Serial transmitter is specified to operate, the output eye pattern of the transmitter shall fall entirely within the unshaded portion of the transmitter output compliance mask shown in Figure 12 with the parameters specified in Table 31 when measured at the output pins of the device and the device is driving a 100 Ω ±5% differential resistive load. The output eye pattern of an LP-Serial transmitter that implements pre-emphasis (to equalize the link and reduce inter-symbol interference) need only comply with the transmitter output compliance mask when pre-emphasis is disabled or minimized.

2.6.5.6 Receiver Eye Diagrams

For each baud rate at which an LP-Serial receiver is specified to operate, the receiver shall meet the corresponding bit error rate specification (Table 32, Table 33, and Table 34) when the eye pattern of the receiver test signal (exclusive of sinusoidal jitter) falls entirely within the unshaded portion of the receiver input compliance mask shown in Figure 14 with the parameters specified in Table 35. The eye pattern of the receiver test signal is measured at the input pins of the receiving device with the device replaced with a 100 Ω ±5% differential resistive load.

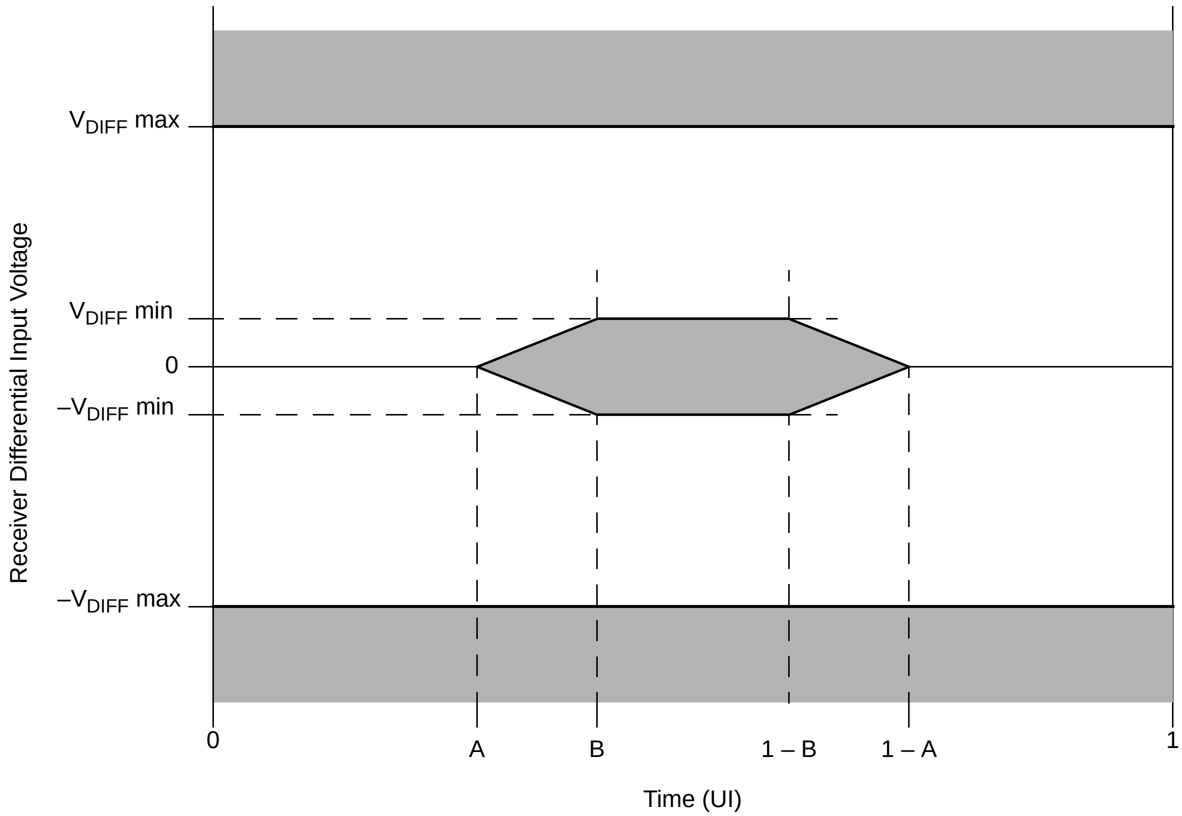

Figure 14. Receiver Input Compliance Mask

Table 35. Receiver Input Compliance Mask Parameters Exclusive of Sinusoidal Jitter

Receiver Type	V_{DIFF}min (mV)	V_{DIFF}max (mV)	A (UI)	B (UI)
1.25 GBaud	100	800	0.275	0.400
2.5 GBaud	100	800	0.275	0.400
3.125 GBaud	100	800	0.275	0.400

2.6.5.7 Measurement and Test Requirements

Since the LP-Serial electrical specification are guided by the XAUI electrical interface specified in Clause 47 of **IEEE** Std. 802.3ae-2002™, the measurement and test requirements defined here are similarly guided by Clause 47. In addition, the CJPAT test pattern defined in Annex 48A of **IEEE** Std. 802.3ae-2002 is specified as the test pattern for use in eye pattern and jitter measurements. Annex 48B of **IEEE** Std. 802.3ae-2002 is recommended as a reference for additional information on jitter test methods.

2.6.5.8 Eye Template Measurements

For the purpose of eye template measurements, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for template measurements is the continuous jitter test pattern (CJPAT) defined in Annex 48A of **IEEE** Std. 802.3ae. All lanes of the LP-Serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than 10^{-12}. The eye pattern shall be measured with AC coupling and the compliance template centered at 0 Volts differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100 Ω resistive ±5% differential to 2.5 GHz.

2.6.5.9 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter Test Pattern (CJPAT) pattern defined in Annex 48A of **IEEE** Std. 802.3ae. All lanes of the LP-Serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 V differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of **IEEE** Std. 802.3ae.

2.6.5.10 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100 Ω resistive ±5% differential to 2.5 GHz.

2.6.5.11 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in **Section 2.6.5.9** and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in Figure 14 and Table 35. Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in Section 8.6 is then added to the signal and the test load is replaced by the receiver being tested.

2.6.6 PCI Timing

This section describes the general AC timing parameters of the PCI bus. Table 36 provides the PCI AC timing specifications.

Table 36. PCI AC Timing Specifications

Parameter	Symbol	33 MHz		66 MHz		Unit
		Min	Max	Min	Max	
Output delay	t_{PCVAL}	2.0	11.0	1.0	6.0	ns
High-Z to Valid Output delay	t_{PCON}	2.0	—	1.0	—	ns
Valid to High-Z Output delay	t_{PCOFF}	—	28	—	14	ns
Input setup	t_{PCSU}	7.0	—	3.0	—	ns
Input hold	t_{PCH}	0	—	0	—	ns

2.6.9 Timer Timing

Table 39. Timer Timing

Characteristics	Symbol	Min	Unit
TIMERx frequency	$T_{TMREFCLK}$	10.0	ns
TIMERx Input high phase	T_{TMCH}	4.0	ns
TIMERx Output low phase	T_{TMCL}	4.0	ns

Figure 23 shows the timer input AC timing

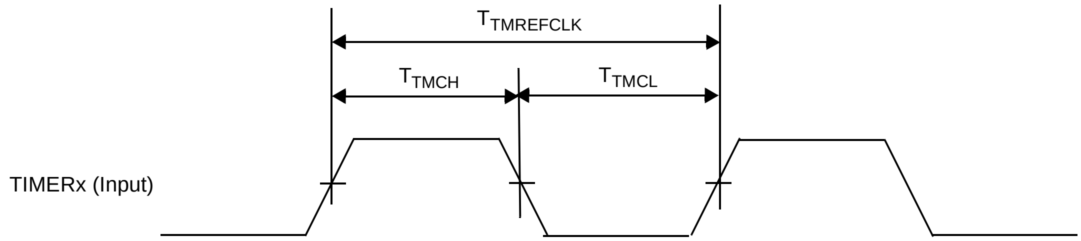

Figure 23. Timer Timing

2.6.10 Ethernet Timing

This section describes the AC electrical characteristics for the Ethernet interface.

There are programmable delay units (PDU) that should be programmed differently for each Interface to meet timing. There is a general configuration register 4 (GCR4) used to configure the timing. For additional information, see the *MSC8144 Reference Manual*.

2.6.10.1 Management Interface Timing

Table 40. Ethernet Controller Management Interface Timing

Characteristics	Symbol	Min	Max	Unit
ETHMDC to ETHMDIO delay[2]	t_{MDKHDX}	10	70	ns
ETHMDIO to ETHMDC rising edge setup time	t_{MDDVKH}	7	—	ns
ETHMDC rising edge to ETHMDIO hold time	t_{MDDXKH}	0	—	ns

Notes:
1. Program the ETHMDC frequency (f_{MDC}) to a maximum value of 2.5 MHz (400 ns period for t_{MDC}). The value depends on the source clock and configuration of MIIMCFG[MCS] and UPSMR[MDCP]. For example, for a source clock of 400 MHz, to achieve f_{MDC} = 2.5 MHz, program MIIMCFG[MCS] = 0x4 and UPSMR[MDCP] = 0. See the *MSC8144 Reference Manual* for configuration details.
2. The value depends on the source clock. For example, for a source clock of 267 MHz, the delay is 70 ns. For a source clock of 333 MHz, the delay is 58 ns.

The following supplies should rise before any other supplies in any sequence

- V_{DD} and V_{DDPLL} coupled together
- V_{DDM3}

After the above supplies rise to 90% of their nominal value the following I/O supplies may rise in any sequence (see Figure 42):

- V_{DDGE1}
- V_{DDGE2}
- V_{DDIO}
- V_{DDDDR} and MV_{REF} coupled one to another. MV_{REF} should be either at same time or after V_{DDDDR}.
- V_{DDM3IO}
- V_{25M3}

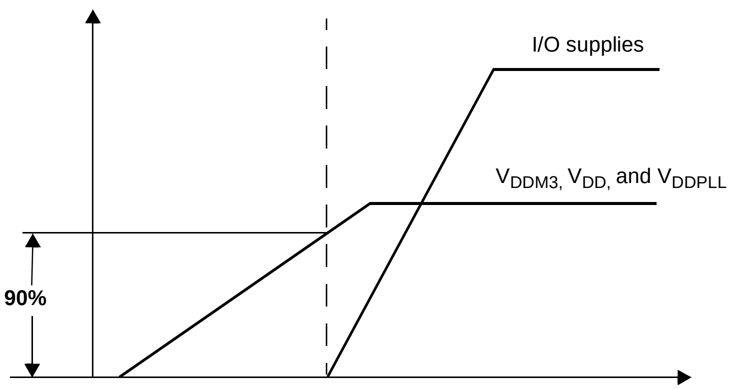

Figure 42. V_{DDM3}, V_{DDM3IO} and V_{25M3} Power-on Sequence

Note:
1. This recommended power sequencing is different from the MSC8122/MSC8126.
2. If no pins that require V_{DDGE1} as a reference supply are used (see Table 1), V_{DDGE1} can be tied to GND.
3. If no pins that require V_{DDGE2} as a reference supply are used (see Table 1), V_{DDGE2} can be tied to GND.
4. If the DDR interface is not used, V_{DDDDR} and MV_{REF} can be tied to GND.
5. If the M3 memory is not used, V_{DDM3}, V_{DDM3IO}, and V_{25M3} can be tied to GND.
6. If the RapidIO interface is not used, V_{DDSX}, V_{DDSXP}, and $V_{DDRIOPLL}$ can be tied to GND.

3.1.2 Start-Up Timing

Section 2.6.1 describes the start-up timing.

3.2 Power Supply Design Considerations

Each PLL supply must have an external RC filter for the V_{DDPLL} input. The filter is a 10 Ω resistor in series with two 2.2 µF, low ESL (<0.5 nH) and low ESR capacitors. All three PLLs can connect to a single supply voltage source (such as a voltage regulator) as long as the external RC filter is applied to each PLL separately (see Figure 43). For optimal noise filtering, place the circuit as close as possible to its V_{DDPLL} inputs. These traces should be short and direct.

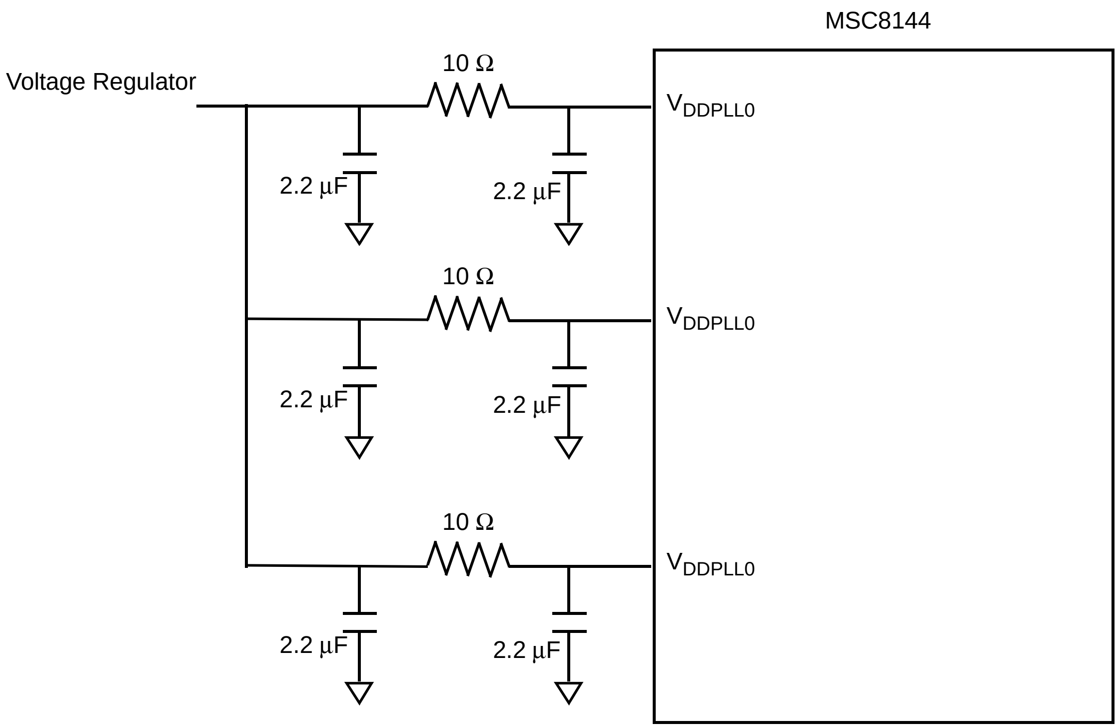

Figure 43. PLL Supplies

3.3 Clock and Timing Signal Board Layout Considerations

When laying out the system board, use the following guidelines:

- Keep clock and timing signal paths as short as possible and route with 50 Ω impedance.
- Use a serial termination resistor placed close to the clock buffer to minimize signal reflection. Use the following equation to compute the resistor value:

  Rterm = Rim – Rbuf

  where Rim = trace characteristic impedance

  Rbuf = clock buffer internal impedance.

Note: See *MSC8144 CLKIN and PCI_CLK_IN Board Layout* (AN3440) for an example layout.

3.4 Connectivity Guidelines

Note: Although the package actually uses a ball grid array, the more conventional term pin is used to denote signal connections in this discussion.

First, select the pin multiplexing mode to allocate the required I/O signals. Then use the guidelines presented in the following subsections for board design and connections. The following conventions are used in describing the connectivity requirements:

1. GND indicates using a 10 kΩ pull-down resistor (recommended) or a direct connection to the ground plane. Direct connections to the ground plane may yield DC current up to 50mA through the I/O supply that adds to overall power consumption.
2. V_{DD} indicates using a 10 kΩ pull-up resistor (recommended) or a direct connection to the appropriate power supply. Direct connections to the supply may yield DC current up to 50mA through the I/O supply that adds to overall power consumption.
3. Mandatory use of a pull-up or pull-down resistor it is clearly indicated as “pull-up/pull-down”.
4. NC indicates “not connected” and means do not connect anything to the pin.
5. The phrase “in use” indicates a typical pin connection for the required function.

Note: Please see recommendations #1 and #2 as mandatory pull-down or pull-up connection for unused pins in case of subset interface connection.

3.4.1 DDR Memory Related Pins

This section discusses the various scenarios that can be used with DDR1 and DDR2 memory.

Note: For information about unused differential/non-differential pins in DDR1/DDR2 modes (that is, unused negative lines of strobes in DDR1), please refer to Table 51.

3.4.1.1 DDR Interface Is Not Used

Table 51. Connectivity of DDR Related Pins When the DDR Interface Is Not Used

Signal Name	Pin Connection
MDQ[0–31]	NC
MDQS[0–3]	NC
$\overline{\text{MDQS[0–3]}}$	NC
MA[0–15]	NC
MCK[0–2]	NC
$\overline{\text{MCK[0–2]}}$	NC
$\overline{\text{MCS[0–1]}}$	NC

Table 58. Connectivity of GE1 Related Pins When only a subset of the GE1 Interface Is required (continued)

Signal Name	Pin Connection
GE1_SGMII_TX	NC
GE1_TD[0-3]	NC
GE1_TX_CLK	GND
GE1_TX_EN	NC
GE1_TX_ER	NC

3.4.4.2 Ethernet Controller 2 (GE2) Related Pins

Note: Table 59 through Table 61 assume that the alternate function of the specified pin is not used. If the alternate function is used, connect the pin as required to support that function.

3.4.4.2.1 GE2 interface Is Not Used

Table 59 assumes that the GE2 pins are not used for any purpose (including any multiplexed function) and that V_{DDGE2} is tied to GND.

Table 59. Connectivity of GE2 Related Pins When the GE2 Interface Is Not Used

Signal Name	Pin Connection
GE2_RD[0-3]	NC
GE2_RX_CLK	NC
GE2_RX_DV	NC
GE2_RX_ER	NC
GE2_SGMII_RX	GND_{SXC}
$\overline{\text{GE2\_SGMII\_RX}}$	GND_{SXC}
$\overline{\text{GE2\_SGMII\_TX}}$	NC
GE2_SGMII_TX	NC
GE2_TCK	Nc
GE2_TD[0–3]	Nc
GE2_TX_EN	NC

3.4.4.2.2 Subset of GE2 Pins Required

When only a subset of the whole GE2 interface is used, such as for RMII, the unused GE2 pins should be connected as described in Table 60. The table assumes that the unused GE2 pins are not used for any purpose (including any multiplexed functions) and that V_{DDGE2} is tied to either 2.5 V or 3.3 V.

Table 60. Connectivity of GE1 Related Pins When only a subset of the GE1 Interface Is required

Signal Name	Pin Connection
GE2_RD[0-3]	GND
GE2_RX_CLK	GND
GE2_RX_DV	GND
GE2_RX_ER	GND
GE2_SGMII_RX	GND_{SXC}

4 Ordering Information

Consult a Freescale Semiconductor sales office or authorized distributor to determine product availability and place an order.

Part	Package Type	Spheres	Mask #	Core Voltage	Operating Temperature	Core Frequency (MHz)	Order Number
MSC8144	Flip Chip Plastic Ball Grid Array (FC-PBGA)	Lead-free	0M31H	1.0 V	0° to 90°C	800	MSC8144VT800A
					0° to 105°C	800	MSC8144SVT800A
					–40° to 105°C	800	MSC8144TVT800A
					0° to 90°C	1000	MSC8144VT1000A
					0° to 105°C	1000	MSC8144SVT1000A
					–40° to 105°C	1000	MSC8144TVT1000A
			1M31H	1.0 V	0° to 90°C	800	MSC8144VT800B
					0° to 105°C	800	MSC8144SVT800B
					–40° to 105°C	800	MSC8144TVT800B
					0° to 90°C	1000	MSC8144VT1000B
					0° to 105°C	1000	MSC8144SVT1000B
					–40° to 105°C	1000	MSC8144TVT1000B
Note: See Table 3 for Core Voltage tolerance limits.							

7 Revision History

Table 66 provides a revision history for this data sheet.

Table 66. Document Revision History

Rev.	Date	Description
0	Feb. 2007	• Initial public release.
1	Apr. 2007	• Adds new I/O multiplexing mode 7 that supports POS functionality. • Updates reference voltage supply for pins G5, H7, and H8 in Table 1. • Updates start-up timing recommendations with regard to $\overline{TRST}$ and $\overline{M3\_RESET}$ in Section 2.7.1. • Adds input clock duty cycles in Table 20. • Updates PCI AC timings in Table 41. • Removes UTOPIA internal clock specifications in Table 52. • Updates JTAG timings in Table 56. • Clarifies connectivity guidelines for Ethernet pins in Section 3.3.4. • Miscellaneous pin connectivity guidelines were updated in Table 71. • Updates name of core subsystem reference manual.
2	June 2007	• Corrected AA4 definition in Table 1. Changed TDM5TD3 to correct name TDM5TDAT. • Removed Figure 35 because the device does not support UTOPIA using an internal clock. Renumbered subsequent figures. • Removed Section 3.5 *Thermal Considerations*. To be replaced with an application note.
3	Sep 2007	• Updated M3 voltage range in Table 3. • Changed note in Table 7 for PLL power supplies. • DDR voltage designator changed from V_{DD} to V_{DDDDR} in Table 8, Table 10, **Section 2.7.4.1**, **Section 2.7.4.2**, and Figure 11. Changed range on I_{OZ} in Table 8 and Table 10. • Deleted text before Table 13 and added note 2 to input pin capacitance. • Deleted text before Table 14, added a 1 to the note, and added note 1 to input pin capacitance. • Deleted **Section 2.6.5** on page 32 and renumbered subsequent subsections. • Deleted text before new **Section 2.6.5.1**. • Added a 1 to the note in Table 15 and added note 1 to input pin capacitance. • Deleted ac voltage rows from Table 16. Added note 1 to input pin capacitance. • Changed output high and low voltage levels in Table 17 and Table 18. • Deleted text before Table 19. • Added clock skew ranges in percent in Table 21. • Changed V_{REF} to MV_{REF} in Table 26. • Changed V_{DD} to V_{DDIO} in Table 41 Updated note 2. • Added note 4 to Table 42. Changed $t_{TDMSHOX}$ value. • Changed V_{DD} to V_{DDGE} in Figure 27 and Figure 30. • Changed the value of the data to clock out skew in Table 51. • Changed EE pin timing in Table 55. • Changed the head for the JTAG timing section, now **Section 2.7.15**. • Updated JTAG timing for TCK cycle time, TCK high phase, and boundary scan input data hold time in Table 56. • Added new **Section 3.3** with guidelines for board layout for clock and timing signals. Renumbered subsequent sections.
4	Sep 2007	• Changed leakage current values in Table 13, Table 14, Table 11, Table 16, Table 17, Table 18, and Table 19 from –10 and 10 µa to –30 and 30 µa. • Change the minimum value of t_{MDDVKH} in Table 45 from 5 ns to 7 ns. • Updated note 1 in Table 45.
5	Oct 2007	• Corrected column numbering in Figure 3 and Figure 4. • Updated SPI signal names in Table 1.
6	Oct 2007	• Updated SPI signal names in Table 1.